

**Notice of References Cited**

Application/Control No.

10/001,920

Applicant(s)/Patent Under  
Reexamination  
AMMANN ET AL.

Examiner

Granvill D Lee, Jr

Art Unit

2825

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6118502	04-1998	Yamazaki et al.	349/45
	B	US-5202273	07-1991	Nakamura	437/40
	C	US-5426850	11-1992	Fukutomi et al.	29/848
	D	US-5455202	01-1993	Malloy et al.	437/228
	E	US-5880065	01-1997	Hayashi et al.	503/227
	F	US-2002/0036055	05-2001	Yoshimura et al.	156/234
	G	US-3181986	03-1961	Pritikin	156/233
	H	US-6423614	06-1998	Doyle	438/458
	I	US-4306925	09-1980	Lebow et al.	156/150
	J	US-5391257	12-1993	Sullivan et al.	156/630
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2001-147240	05-2001	Japan	--	G01R 1/073
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.